

ECLTRG TC timing Calibration and Event Timing Study

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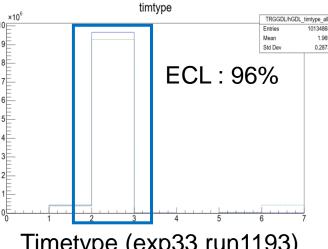


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EventT0



- EventT0 is relative time difference between event timing and trigger timing.
 - EventT0 = (event timing) (trigger timing)
- SVD sampling is affected by EventT0 resolution
 - In higher luminosity environment, the number of sampling points should be reduced(because of deadtime).
 - For 3points sampling, < 10ns is required but current resolution > 10ns for E < 500MeV.
- ECLTRG may improve resolution from trigger side
 - Most of trigger timing(~95%) is determined by ECLTRG in exp33.
 - Trigger timing with consistent quality: TC timing calibration
 - Improve trigger timing itself: ECLTRG timing determination logic



Timetype (exp33 run1193)

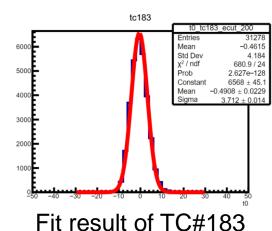


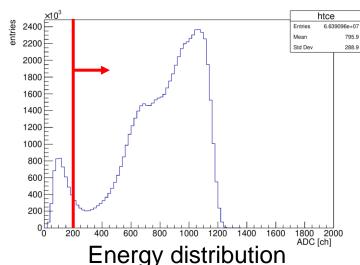
Method

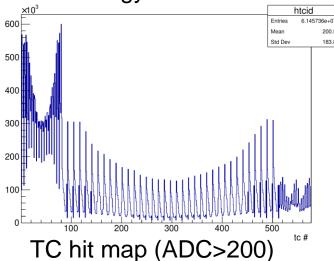
- ECL trigger timing is determined by the most energetic TC timing
- EventT0 = (subdetector timing) (the most energetic TC timing)
 Event timing trigger timing
- EventT0 of each TC ~ timing of the TC
- Fitting to extract calibration constants (chi2 gaussian fit)

Data

- All runs in prerelease-07-00-00d/s-proc4_cDST/e0026
- Skimmed by Bhabha_calib
- TimeType = ECL
- EventT0 per each TC
- TC ID: 1-576
- TC energy > 200 ADC(~1GeV)

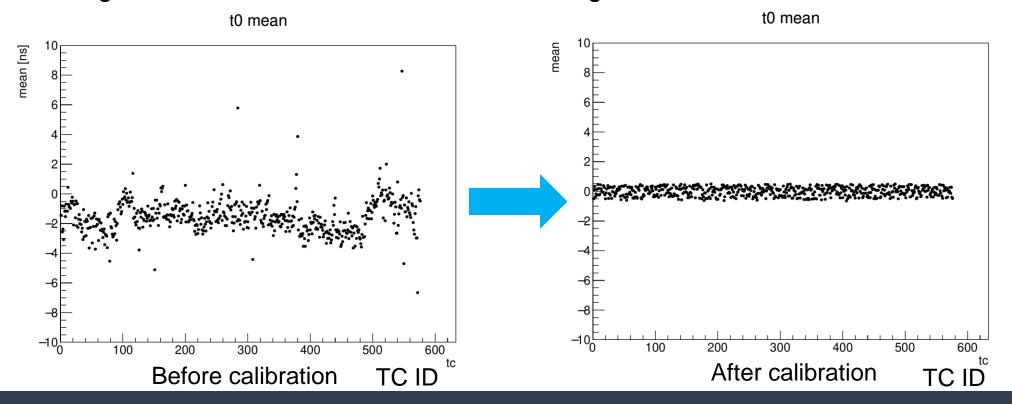






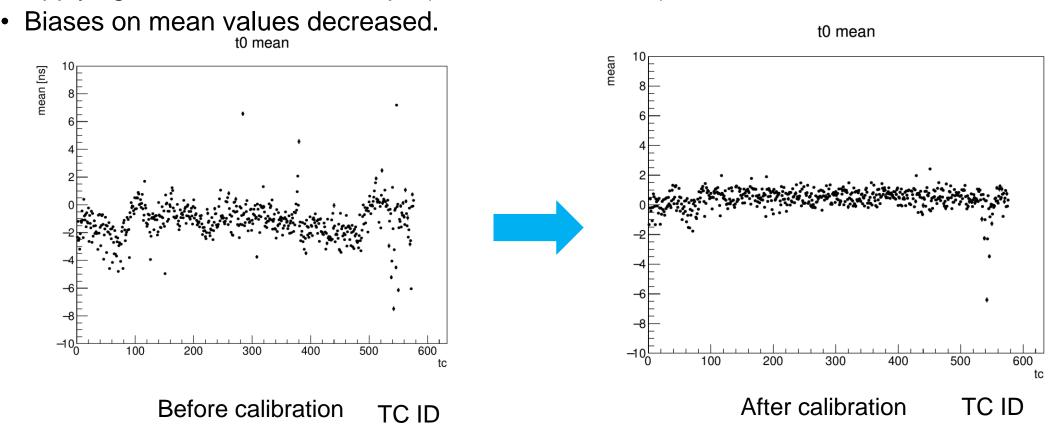


- Calibration : $(t0_{i, cal} = t0_i C_i)$, i = TC ID
 - C_i is calibration constant calculated by the fitting: $(t0_{i, cal}) = 0$
 - FAM does not accept floating number so C_i needs to be integer
 - Checking that calibration constants work well using bhabha_calib skimmed data





- Calibration test
 - Using C_i obtained by Bhabha samples
 - Applying to hadron_calib sample(with cut ADC > 200)

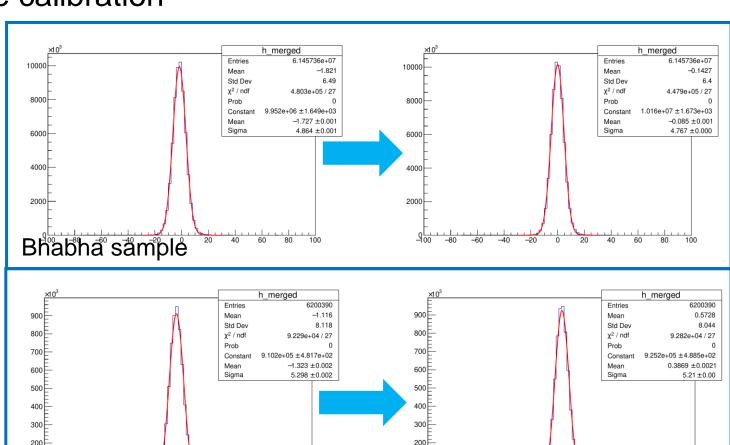




- Expected EventT0 variation by the calibration
 - Bare EventT0(all TC merged)
 - Timetype = ECL

Samples	EventT0	Before	After
Bhabha (Ref.)	Mean	-1.73	-0.09
	Width	4.86	4.77
Hadron (test)	Mean	-1.32	0.39
	Width	5.30	5.21

- For hadron sample
 - Mean bias reduced about 1ns
 - Stddev reduced about 2%.

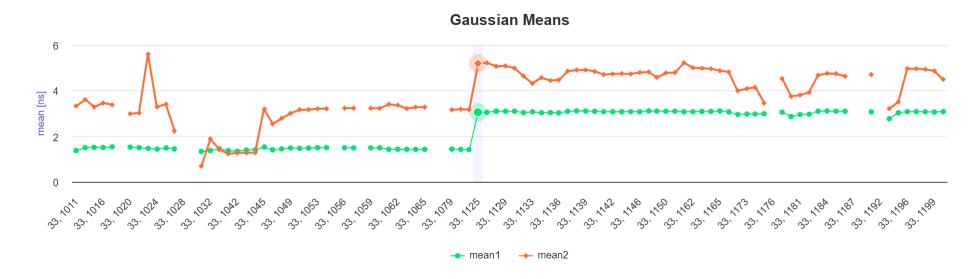


Hadron sample



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Calibration constants had been updated to FAM since exp33 run1083

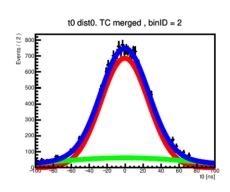


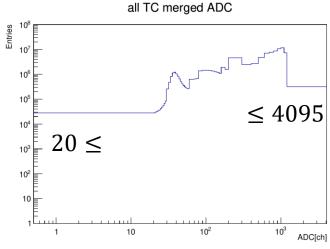
Might need to update constants with recent experiment number

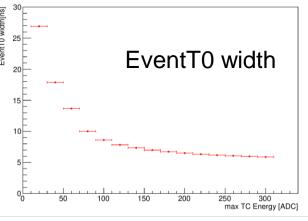


In low energy region, energy dependent calibration would yield better resolution.

- Data
 - All runs in prerelease-07-00-00d/s-proc4_cDST/e0026
 - bhabha_calib, hadron_calib, radmumu_calib and tight_mumu_or_highmu_calib
 - TimeType = ECL
- Method
 - 50 binning for 12bits ADC[0,4095]
 - Dense binning for low energy and coarse binning for high energy
 - EventT0 per each energy bin(50 distributions)
 - Fitting by binned likelihood fit
 - 2 Gaussian sharing mean with different sigma
 - Calibration by odd number runs
 - Test by even number runs

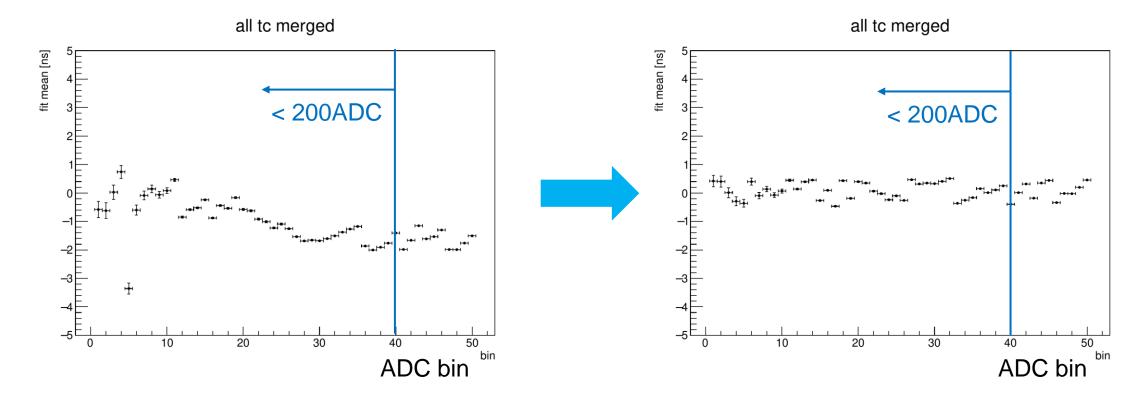








- Calibration : $(t0_{i, cal} = t0_i C_i)$, i = ADCbin
 - C_i (integer) is calibration constant calculated by the fitting: $(t0_{i, cal}) = 0$
 - Checking that calibration constants work well using odd number runs

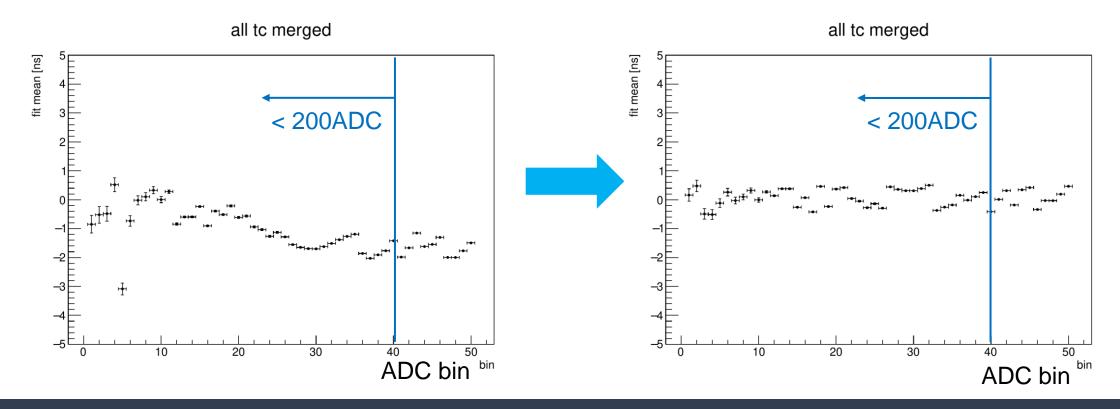




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Calibration test

- Using C_i obtained by odd number runs
- Applying to even number runs
- Biases on mean values decreased.





- Effectivity in low energy regions
 - Before calibration
 - After energy dependent calibration
 - TC by TC calibration(obtained with ADC > 200)





fit mean [ns]	5	1 -	calibration
fit me	3E 3E	T TC by	Ilibration
	1		
			-
	-1E		-
	_3		
	50 50 100 150 200	250	300 ADC [ch]

Low Energy region

ADC < 300 Calibration result					
Samples	EventT0	Before	E dep.	TC by TC	
Odd (Ref.)	Mean	-1.69	0.01	-0.02	
	Width	7.31	7.30	7.22	
Even (test)	Mean	-1.69	0.01	-0.02	
	Width	7.32	7.31	7.23	



- For all energy regions
 - The same behavior in low energy region can be seen.
 - TC by TC calibration seems to be better for now.

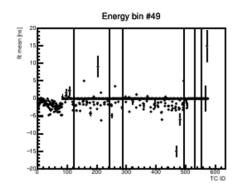
All E Calibration result						
Samples	EventT0	Before	E dep.	TC by TC		
Odd (Ref.)	Mean	-1.69	0.01	-0.02		
	Width	7.31	7.22	7.13		
Even (test)	Mean	-1.69	0.00	-0.03		
	Width	7.32	7.22	7.14		

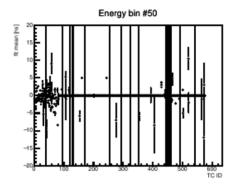
Fittings for the table are in backup

TC by TC - Energy Dependent Calibration

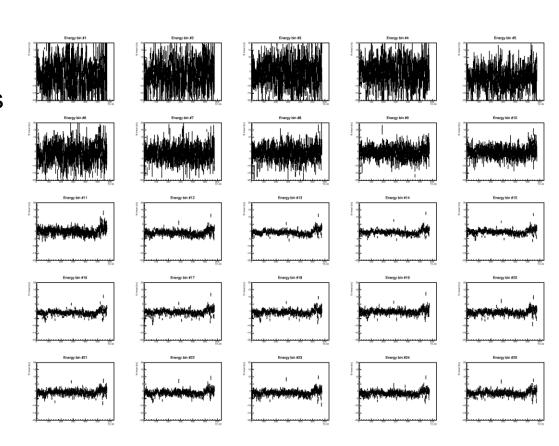


- Calibration : $(t0_{ij, cal} = t0_{ij} C_{ij})$, i = TCID , j = ADCbin
- Fitting result of first 25 energy bins
 - One figure representing one Energy bin
 - X axis = TCID, Y axis = common mean of gaussians
- Too low statistics for low energy TC
 - Yielding too big calibration constants
- Fitting failure in high energy bins





Need more study to use this calibration method

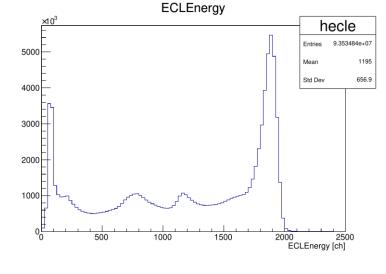


Trigger Timing Determination Logic



Data

- All runs in prerelease-07-00-00d/s-proc4_cDST/e0026
- bhahba_all_calib, hadron_calib, radmumu_calib and tight_mumu_or_highmu_calib
- TimeType = ECL
- Energy weighted trigger timing from ECL
 - (trigger timing) = $\frac{\sum_{i}^{N} E_{i} t_{i}}{\sum_{i}^{N} E_{i}}$
 - Subscript i means TC number, E_i is TC energy and t_i is TC timing
 - summing up to N'th energetic TC

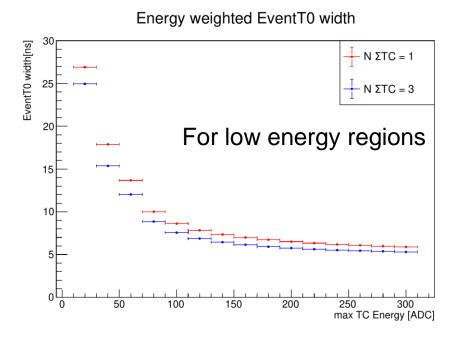


EventT0 = CurrentEventT0 + (most energetic TC timing) – (energy weighted trigger timing)
 Current trigger timing method

Energy Weighted Trigger Timing



- N=3: If nTCs < 3, N = nTCs and if nTCs => 3, N=3
- In low energy regions, 8-15% of improvement on resolution
- In all energy regions, ~12% of improvement



For all energy regions

Energy weighted to with different N

Further study is ongoing.

Summary & To Do



- TC Timing Calibration
 - TC by TC : Bias on EventT0 ↓, 2% of improvement on EventT0 resolution
 - Energy dependent : Bias on EventT0 ↓
 - TC by TC Energy dependent
 - Applying sequentially
- Event Timing
 - Energy weighted trigger timing : for N = 3, about 10% of improvement on resolution
 - Change of N
 - Other methods that can be applied on FPGA

backup



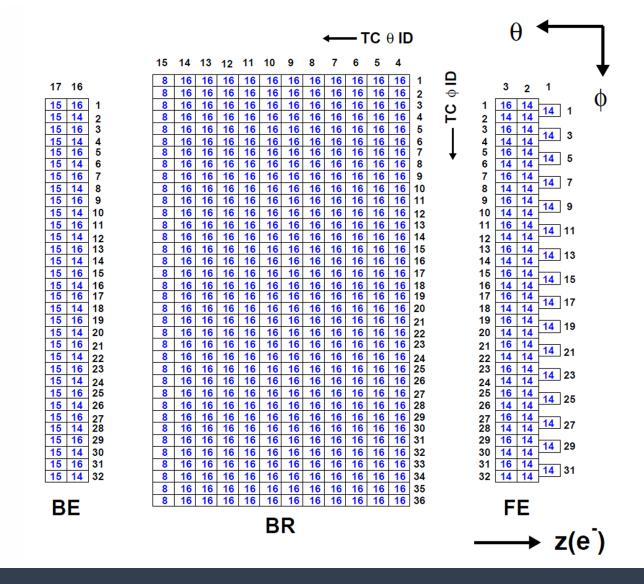
ECL trigger



- ~9000 CsI(TI) crystal
- 576 Trigger Cells (TCs)
- DSPshaper -> FAM -> TMM -> ETM -> GRL/GDL
 - FAM: FADC Analysis Module
 - TMM : Trigger Merger Module
 - ETM : ECL Trigger Master
- FAM determine timing and energy of TC
 - Timing of TC: mainly FADC waveform fitting
 - E ~ 5 MeV / ADC

TC map





Binning definition



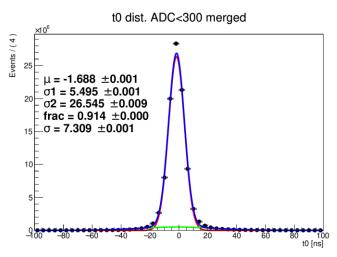
• 50 bins

[0,20], [21], [22], [23], [24], [25], [26], [27], [28], [29],
[30,31], [32,33], [34,35], [36,37], [38,39], [40,41], [42,43], [44,45], [46,47], [48,49],
[50,51], [52,53], [54,55], [56,57], [58,59], [60,64], [65,69], [70,74], [75,79], [80,89],
[90,99], [100,109], [110,119], [120,129], [130,139], [140,149], [150,159], [160,179],
[180,199], [200,299], [300,399], [400,499], [500,599], [600,699], [700,799],
[800,899], [900,999], [100,1099], [1100,1199], [1200,4095]

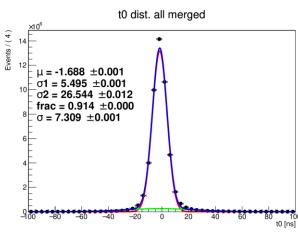
E dep. Calibration fitting

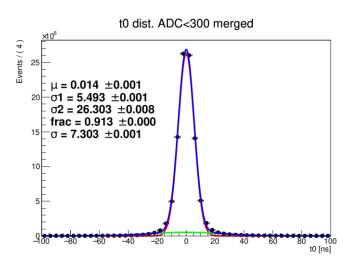


Odd number runs

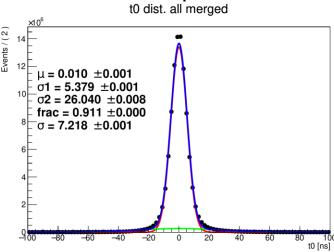


before

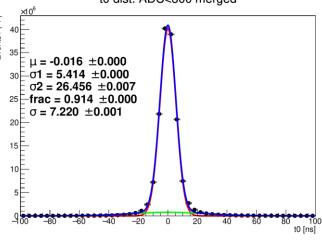




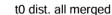
E dep.

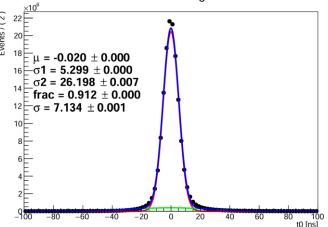


t0 dist. ADC<300 merged



TC by TC





E dep. Calibration fitting



• Even number runs

